



Certificate of Analysis

ULTRAGrade™ Solution
Silicon ICP Standard
10000 µg/mL

Catalog Number: ICP-114
Lot Number: J00332
Job Number: J00008073
Lot Issue Date: 04/01/2008
Expiration Date: 05/31/2015

Starting Material: Ammonium Hexafluorosilicate
Starting Material Purity: 99.999%
Starting Material Lot No.: BH00801
Matrix: 2% nitric acid, and trace hydrofluoric acid, in low TOC water (< 50 ppb)
Atomic Weight Si: 28.09

Certified Value: 10008 ± 20 µg/mL

This Certified Reference Material (CRM) was manufactured and verified in accordance with ULTRA's ISO 9001:2000 registered quality system, and the analyte concentrations were verified by our ISO 17025 accredited laboratory. The certified value and uncertainty value, at the 95% confidence level, for each analyte determined gravimetrically.

Classical Wet Assay Method: Theoretical, based on gravimetric measurements

Confirmation by Inductively Coupled Plasma Spectroscopy (ICP / ICP-MS) vs. NIST SRM 3150

ULTRA uses purified acids, 18 megohm double deionized water, calibrated Class A glassware & meticulously cleaned bottles in the manufacturing of ULTRAGrade standards. Balances used in the manufacturing of this standard are calibrated with weights traceable to NIST in compliance with ANSI/NCCL Z-540-1 and ISO 9001

Trace Metallic Impurities in Solution Standard in µg/mL:

* Al <0.010 D	* Ga <0.005 ND	n Nb	n S
* Sb <0.005 ND	n Ge	n Os	n Ta
* As <0.005 ND	n Au	n Pd <0.005 ND	n Te
* Ba <0.010 D	n Hf	* P <0.005 ND	n Tb
* Be <0.005 ND	n Ho	* Pt <0.005 ND	* Tl <0.005 ND
* Bi <0.005 ND	* In <0.005 ND	* K <0.005 ND	n Th
* B <0.005 ND	n Ir	n Pr	n Tm
* Cd <0.010 D	* Fe <0.010 D	n Re	* Sn <0.005 ND
* Ca <0.010 D	* La <0.005 ND	n Rh	* Ti <0.010 D
n Ce	* Pb <0.005 ND	n Rb	n W
n Cs	* Li <0.005 ND	n Ru	n U
* Cr <0.005 ND	n Lu	n Sm	* V <0.005 ND
* Co <0.005 ND	* Mg <0.005 ND	n Sc	n Yb
* Cu <0.005 ND	* Mn <0.005 ND	* Se <0.005 ND	n Y
n Dy	* Hg <0.005 ND	s Si	* Zn <0.010 D
* Er <0.005 ND	* Mo <0.005 ND	* Ag <0.005 ND	n Zr
* Eu <0.005 ND	n Nd	* Na <0.005 ND	
* Gd <0.005 ND	* Ni <0.005 ND	* Sr <0.005 ND	

* - element checked for
ND - not detected

i - spectral interference
D - detected

n - not checked for
s - solution standard element

Density of Solution (measured at 20.0°C ± 0.5°C): 1.043 g/mL



ISO 9001 Registered Quality System – TUV USA

William J. Leary
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